

C1812C102JFTACAUTO

SMD Auto X8G HVHT150C, Ceramic, 1,000 pF, 5%, 1,500 VDC, X8G, SMD, MLCC, High Voltage, High Temperature, Ultra-Stable, Automotive Grade, 1812, 2.3 mm



General Information	
Series	SMD Auto X8G HVHT150C
Style	SMD Chip
Description	SMD, MLCC, High Voltage, High Temperature, Ultra-Stable, Automotive Grade
Features	High Temperature, Ultra-Stable, Automotive Grade
RoHS	Yes
Termination	Tin
Marking	No
Qualifications	AEC-Q200
AEC-Q200	Yes
Typical Component Weight	67 mg
Shelf Life	78 Weeks
MSL	1

Dimensions	
Chip Size	1812
L	4.5mm +/-0.3mm
W	3.2mm +/-0.3mm
T	1.4mm +/-0.15mm
S	2.3mm MIN
В	0.6mm +/-0.35mm

1	1.4mm +/-0.15mm	voltage DC	1500 VDC
S	2.3mm MIN	Dielectric Withstanding Voltage	1,800 VDC
В	0.6mm +/-0.35mm	Temperature Range	-55/+150°C
		Temp. Coefficient	X8G
Packaging Specifications		Capacitance Change with	30 ppm/C, 1Me
Packaging	T&R, 180mm, Plastic Tape	Reference to +25°C and 0 VDC Applied (TCC)	
Packaging Quantity	1000	Dissipation Factor	0.1% 1 MHz 1.0Vr

Specifications	
Capacitance	1,000 pF
Measurement Condition	1 MHz 1.0Vrms
Tolerance	5%
Voltage DC	1500 VDC
Dielectric Withstanding Voltage	1,800 VDC
Temperature Range	-55/+150°C
Temp. Coefficient	X8G
Capacitance Change with Reference to +25°C and 0 VDC Applied (TCC)	30 ppm/C, 1MegaHz 1.0Vrms
Dissipation Factor	0.1% 1 MHz 1.0Vrms
Aging Rate	0% Loss/Decade Hour: Referee Time is 1000 Hours
Insulation Resistance	100 GOhms

Statements of suitability for certain applications are based on our knowledge of typical operating conditions for such applications, but are not intended to constitute - and we specifically disclaim - any warranty concerning suitability for a specific customer application or use. This Information is intended for use only by customers who have the requisite experience and capability to determine the correct products for their application. Any technical advice inferred from this Information or otherwise provided by us with reference to the use of our products is given gratis, and we assume no obligation or liability for the advice given or results obtained.

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